


<b>Search Notes</b>  	<b>Application/Control No.</b>  10674834	<b>Applicant(s)/Patent Under Reexamination</b>  BITSCH ET AL.
	<b>Examiner</b>  Ly, Anh	<b>Art Unit</b>  2162

SEARCHED			
Class	Subclass	Date	Examiner
707	3, 4, 6 and 10	12/06/2007	AL
717	127, 136 and 163	12/06/2007	AL
715	522 and 530	12/06/2007	AL

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (US PGPUB, USPAT, EPO, JPO, DERWENT and IBM_TDB)	12/06/2007	AL
ACM/Google.com/IEEE	12/06/2007	AL
related application search	12/06/2007	AL
Consulted: Jean Corrielus: (needing interview for claimed invention)	12/06/2007	AL

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner